


<b>Search Notes</b>  	<b>Application/Control No.</b>  10584503	<b>Applicant(s)/Patent Under Reexamination</b>  VAN DER TUIJN ET AL.
	<b>Examiner</b>  JEFFREY PARKER	<b>Art Unit</b>  4147

SEARCHED			
Class	Subclass	Date	Examiner
375	340,342,316,317	05/08/2009	JP
358	283,280,284,282	05/08/2009	JP
375	230	10/4/2010	EMF

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor Name Search	05/1/2009	JP
Updated Search	12/17/2009	JP
Class/subclass search in EAST	10/4/2010	EMF
Inventor name/double patenting search in EAST	10/4/2010	EMF
Keyword search in EAST	10/4/2010	EMF
Updated keyword search in EAST	6/7/2011	EMF
Interference keyword search in EAST	9/16/2011	EMF

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
375	230	9/16/2011	EMF

/ERIN FILE/  
Examiner,Art Unit 2611